# ECEN 325 Lab 7: Characterization and DC Biasing of the BJT

## Objectives

The purpose of this lab is to characterize NPN and PNP bipolar junction transistors (BJT), and to analyze and design DC biasing circuits to set the DC operating point of BJTs.

# Introduction

Figure 1 shows typical symbols for the NPN and PNP BJTs. Depending on the applied DC bias, BJT has three regions of operation:

- **Cutoff Region:** If both base-emitter and base-collector junctions are reverse biased, the BJT enters the cutoff region. All terminal currents are extremely small, and the transistor is off.
- Active Region: The base-emitter junction is forward biased, and the base-collector junction is reverse biased to make a BJT operate in the active region. The active region is used to design a linear amplifier.
- **Saturation Region:** When both the base-emitter and base-collector junctions are forward biased, the BJT enters the saturation region.



Figure 1: Bipolar junction transistor (BJT) (a) NPN (b) PNP

In the active region, the collector current ( $I_C$ ) of NPN and PNP devices are exponential functions of base-emitter voltage ( $V_{BE}$ ) and emitter-base voltage ( $V_{EB}$ ), respectively, given by

$$I_{C,npn} = I_S e^{V_{BE}/V_T} \qquad I_{C,pnp} = I_S e^{V_{EB}/V_T}$$
(1)

where  $I_S$  is the saturation current and  $V_T$  is the thermal voltage, which is approximately 25mV at room temperature. For both NPN and PNP, the base current  $I_B$  is a small fraction of  $I_C$ , given by

$$I_B = \frac{I_C}{\beta} \tag{2}$$

and the emitter current  $I_E$  is the sum of the base and collector currents, given by

$$I_E = I_C + I_B = (\beta + 1)I_B = \frac{I_C}{\alpha}$$
(3)

where

$$\alpha = \frac{\beta}{\beta + 1} \tag{4}$$

 $\beta$  is known as the current gain of the transistor, which varies significantly with temperature, and it can be different between two transistors of the same type. Typical value of  $\beta$  is around 100, resulting in  $\alpha$  = 0.99.

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#### **BJT Characterization**

Figure 2 shows a characterization circuit for an NPN BJT. To obtain  $I_C$  as a function of  $V_{BE}$ ,  $V_1$  is swept while  $V_2$  is kept constant, resulting in the exponential function in Fig. 3(a). If  $V_1$  is kept constant and  $V_2$  is swept,  $I_C$  can be obtained as a function of  $V_{CE}$  as shown in Fig. 3(b).



Figure 2: NPN BJT characterization circuit



Figure 3: Collector current ( $I_C$ ) of an NPN BJT as a function of (a)  $V_{BE}$  (b)  $V_{CE}$ 

Characterization circuit for a PNP BJT is shown in Fig. 4. Keeping  $V_2$  constant and sweeping  $V_1$  provides  $I_C$  as an exponential function of  $V_{EB}$  as shown in Fig. 5(a). Sweeping  $V_2$  while  $V_1$  is kept constant provides the  $I_C$  vs.  $V_{EC}$  characteristics as shown in 5(b).



Figure 4: PNP BJT characterization circuit



Figure 5: Collector current ( $I_C$ ) of a PNP BJT as a function of (a)  $V_{EB}$  (b)  $V_{EC}$ 

#### **BJT DC Biasing - Resistive**

Figures 6(a) and (b) show typical resistive biasing circuits for NPN and PNP transistors, respectively.



Figure 6: Resistive DC biasing circuit for (a) NPN (b) PNP

For each circuit in Figs. 6(a) and (b), assume that the transistor is active, and  $I_B$  is negligible, which means  $R_{B1}$  and  $R_{B2}$  form a voltage divider to set the  $V_2$  voltage. Therefore,  $I_E$  and  $I_C$  can be found as

$$V_2 \approx \frac{R_{B2}}{R_{B1} + R_{B2}} (V_{CC} + V_{EE}) \Rightarrow I_E = \frac{V_2 - 0.7}{R_E} \approx I_C$$
 (5)

All assumptions must be verified to complete the DC analysis. For the circuits in Figs. 6(a) and (b),  $I_B$  is negligible only if  $I_B \ll I_{RB1}$ , which requires

$$I_B = \frac{I_C}{\beta} \ll I_{RB1} \approx \frac{V_{CC} + V_{EE}}{R_{B1} + R_{B2}}$$
(6)

To verify that the NPN transistor is active,  $V_{CE} \ge V_{CE,sat}$  should be satisfied as follows

$$V_{CE} = V_{CC} + V_{EE} - I_C(R_C + R_E) \ge V_{CE,sat}$$

$$\tag{7}$$

For the PNP transistor, active operation requires  $V_{EC} \ge V_{EC,sat}$  as follows

$$V_{EC} = V_{CC} + V_{EE} - I_C R_C + R_E \ge V_{EC,sat}$$

$$\tag{8}$$

where  $V_{CE,sat} \approx V_{EC,sat} \approx 0.2V$ 

#### **BJT DC Biasing - Current Source**

An alternative method for BJT DC biasing is to use a current source connected to the emitter terminal, which directly sets the  $I_E$  current, and hence the  $I_C$  current. Figure 7(a) shows the DC biasing of an NPN BJT using a current source, which can be realized using the circuits in Fig. 7(b) or (c). Figure 8 shows the DC biasing circuit of a PNP BJT using a current source, as well as current source and current mirror realizations.



Figure 7: (a) DC biasing circuit for an NPN BJT using a current source (b) Current source (c) Current mirror



Figure 8: (a) DC biasing circuit for a PNP BJT using a current source (b) Current source (c) Current mirror

For the current sources in Figs. 7(b) and 8(b),  $I_x$  can be calculated as

$$V_{y} \approx \frac{R_{2}}{R_{1} + R_{2}} (V_{CC} + V_{EE}) \Rightarrow I_{x} \approx \frac{V_{y} - 0.7}{R_{3}}$$

$$\tag{9}$$

For the current mirrors in Figs. 7(c) and 8(c), assuming matching transistors and  $R_5 = R_6$ ,  $I_x$  can be calculated as

$$I_x \approx \frac{V_{CC} + V_{EE} - 0.7}{R_4 + R_5}$$
(10)

All transistors in Figs. 7 and 8 are assumed to be active, and all  $I_B$  currents are assumed to be negligible. These assumptions need to be verified after finding the DC solution.

### Calculations

1. Design the circuits in Figs. 6(a) and 6(b) with the following specifications:

NPN		PNP	
I <sub>C</sub>	1mA	I <sub>C</sub>	1mA
V <sub>C</sub>	3.5 <i>V</i>	V <sub>C</sub>	1.5 <i>V</i>
V <sub>CE</sub>	$\geq 1V$	$V_{EC}$	$\geq 1V$
$V_{RE}$	$\geq 1V$	$V_{RE}$	$\geq 1V$
V <sub>CC</sub>	5 <i>V</i>	V <sub>CC</sub>	5 <i>V</i>
$V_{EE}$	0	$V_{EE}$	0
$\beta$	100	$\beta$	100
$V_T$	25 <i>mV</i>	V <sub>T</sub>	25 <i>mV</i>
I <sub>supply</sub>	$\leq 2mA$	I <sub>supply</sub>	$\leq 2mA$

For both circuits, DC biasing should be insensitive to variations in  $\beta$  and  $|V_{BE}|$ , and  $I_B$  currents should be designed to be negligible.

**2.** Design the circuits in Figs. 7(a) and 8(a) using the current sources in Figs. 7(b) and 8(b), respectively, with the following specifications:

NPN		PNP	
$I_C$	2mA	I <sub>C</sub>	2mA
V <sub>C</sub>	3.5 <i>V</i>	V <sub>C</sub>	1.5 <i>V</i>
V <sub>CE</sub>	$\geq 1V$	V <sub>EC</sub>	$\geq 1V$
$V_x$	$\geq 1.5V$	$V_x$	$\geq 1.5V$
V <sub>CC</sub>	5 <i>V</i>	V <sub>CC</sub>	5 <i>V</i>
V <sub>EE</sub>	0	$V_{EE}$	0
β	100	β	100
V <sub>T</sub>	25 <i>mV</i>	VT	25 <i>mV</i>
I <sub>supply</sub>	$\leq 5mA$	I <sub>supply</sub>	$\leq 5 mA$

For both circuits, DC biasing should be insensitive to variations in  $\beta$  and  $|V_{BE}|$ , and  $I_B$  currents should be designed to be negligible.

## Simulations

For all simulations, provide screenshots showing the schematics and the plots with the simulated values properly labeled.

- 1. Draw the schematics for the NPN characterization circuit in Fig. 2 using the 2N3904 transistor
  - Perform a **DC** sweep of  $V_1$  from 0 to 5V, while  $V_2 = 5V$ . Export the simulation data to Excel, and plot  $I_C$  as a function of  $V_{BE}$ .
  - Perform a **DC** sweep of  $V_2$  from 0 to 5V, while  $V_1 = 2V$ . Export the simulation data to Excel, and plot  $I_C$  as a function of  $V_{CE}$ .
- 2. Draw the schematics for the PNP characterization circuit in Fig. 4 using the 2N3906 transistor
  - Perform a **DC** sweep of  $V_1$  from -5V to 0, while  $V_2 = -5V$ . Export the simulation data to Excel, and plot  $I_C$  as a function of  $V_{EB}$ .
  - Perform a **DC sweep** of  $V_2$  from -5V to 0, while  $V_1 = -2V$ . Export the simulation data to Excel, and plot  $I_C$  as a function of  $V_{EC}$ .
- **3.** Draw the schematics in Figs. 6(a) and 6(b) using the calculated component values and 2N3904 and 2N3906 transistors. For both circuits, perform **DC operating point** or **interactive simulation** to obtain the **DC solution** for *I*<sub>*C*</sub>, *V*<sub>*C*</sub>, *V*<sub>*RE*</sub> and *V*<sub>2</sub>.
- **4.** Draw the schematics in Figs. 7(a) and 8(a) using the current sources in Figs. 7(b) and 8(b), respectively, with the calculated component values and 2N3904 and 2N3906 transistors. For both circuits, perform **DC operating point** or **interactive simulation** to obtain the **DC solution** for *I*<sub>C</sub>, *V*<sub>2</sub>, *V*<sub>x</sub> and *V*<sub>y</sub>.

### Measurements

For all measurements, provide screenshots showing the plots with the measured values properly labeled.

- 1. Build the NPN characterization circuit in Fig. 2 using the 2N3904 transistor
  - Apply a ramp signal from 0 to 5V at 1Hz for  $V_1$  while  $V_2 = 5V$ . Export the voltage measurements from the scope to Excel, and plot  $I_C$  as a function of  $V_{BE}$ .
  - Apply a ramp signal from 0 to 5V at 1Hz for  $V_2$  while  $V_1 = 2V$ . Export the voltage measurements from the scope to Excel, and plot  $I_C$  as a function of  $V_{CE}$ .
- 2. Build the PNP characterization circuit in Fig. 4 using the 2N3906 transistor
  - Apply a ramp signal from -5V to 0 at 1Hz for  $V_1$  while  $V_2 = -5V$ . Export the voltage measurements from the scope to Excel, and plot  $I_C$  as a function of  $V_{EB}$ .
  - Apply a ramp signal from -5V to 0 at 1Hz for  $V_2$  while  $V_1 = -2V$ . Export the voltage measurements from the **scope** to Excel, and plot  $I_C$  as a function of  $V_{EC}$ .
- **3.** Build the circuits in Figs. 6(a) and 6(b) using the calculated component values and 2N3904 and 2N3906 transistors. For both circuits, measure the **DC** values for *I*<sub>*C*</sub>, *V*<sub>*C*</sub>, *V*<sub>*RE*</sub> and *V*<sub>2</sub> using the **voltmeter** or **scope**.
- **4.** Build the circuits in Figs. 7(a) and 8(a) using the current sources in Figs. 7(b) and 8(b), respectively, with the calculated component values and 2N3904 and 2N3906 transistors. For both circuits, measure the **DC** values for  $I_C$ ,  $V_C$ ,  $V_2$ ,  $V_x$  and  $V_y$  using the **voltmeter** or **scope**.

### Report

- 1. Include all measurement plots.
- 2. Prepare a table showing calculated, simulated and measured results.
- **3.** Compare the results and comment on the differences.

# Demonstration

- **1.** Calculations and simulations must be submitted on Canvas as a single pdf file **before** the lab session. All simulation plots must include a timestamp.
- 2. Your name and UIN must be written on the side of your breadboard.
- 3. For the NPN characterization circuit in Fig. 2:
  - Apply a ramp 0 to 5V at 1Hz for  $V_1$  while  $V_2 = 5V$ , and export the measurements from scope to Excel.
  - Plot  $I_C$  as a function of  $V_{BE}$  in Excel.
- 4. For the PNP characterization circuit in Fig. 4:
  - Apply a ramp -5V to 0 at 1Hz for  $V_2$  while  $V_1 = -2V$ , and export the measurements from scope to Excel.
  - Plot  $I_C$  as a function of  $V_{EC}$  in Excel.
- 5. For the resistive NPN and PNP biasing circuits in Figs. 6(a) and 6(b):
  - Measure the DC voltages  $V_C$ ,  $V_B$ ,  $V_E$ .
  - Calculate  $I_C$  from the voltage measurements.
- 6. For the current-source NPN and PNP biasing circuits in Figs. 7(a)&(b) and 8(a)&(b):
  - Measure the DC voltages  $V_C$ ,  $V_B$ ,  $V_E$  for both transistors.
  - Calculate  $I_C$  from the voltage measurements.